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| Notice of References Cited | Application/Control No. 09/593,215 | Applicant(s)/Patent Under Reexamination HEINONEN ET AL. | |
| | Examiner PHUC H TRAN | Art Unit 2666 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,101,173 | 08-2000 | Bayley, Gwain | 370/311 |
| | B | US-3,780,230 | 12-1973 | Bowen et al. | 340/825.74 |
| | C | US-6,738,393 | 05-2004 | Miki et al. | 370/506 |
| | D | US-6,480,558 | 11-2002 | Ottosson et al. | 375/350 |
| | E | US-5,610,953 | 03-1997 | Betts et al. | 375/373 |
| | F | US-5,610,953 | 03-1997 | Betts et al. | 375/373 |
| | G | US-6,351,498 | 02-2002 | Yamao et al. | 375/260 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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